Zyvex NanoEffectector® Probes
Nanoscale Probes for Zyvex Nanomanipulator Systems

Features and Benefits
There are two major challenges with probing at the nanoscale: probing small features (50 nm contact) and probing small geometries (four 50 nm contacts within 100 nm of each other). Zyvex’s NanoEffectector Probes are designed to overcome both of these challenges. Their tip radius is better than 50 nm and allows for probing of extremely small features. The probes also have a high aspect ratio (length to diameter) which allows up to 8 probe tips within a 500 nm workspace. NanoEffectector Probes are the most versatile and reliable probes on the market.

Applications
- Electrical characterization of nanostructures for R&D
- Electrical characterization of integrated circuits for failure analysis
- Micro- and nanoscale assembly
- Sample preparation and positioning
- Basic nanomanipulation
- Surface science experiments
- Application notes are available at www.zyvex.com.

Technical Specifications
- Material: Polycrystalline Tungsten Wire
- Length: 14mm
- Shank diameter: 0.25 mm
- Effective tip radius: Better than 50 nm
- Average tip radius: 40 nm
- Effective taper angle: Less than 15°
- Average taper angle: 8°
- Tungsten purity: 99.9%

Note: Probes undergo a rigorous batch-by-batch inspection according to established statistical process control (SPC) standards. We qualify each batch of probes in an SEM for tip radius and taper angle.

Order Lead Time
- Up to 100 probes: 6 weeks
- More than 100 probes: Call for lead time

Note: There is a minimum order quantity of 20 probes.

To place an order, call us toll-free at 1.877.ZYVEX99 (1.877.998.3999) ext. 271 or direct at 972.792.1671. For the most up-to-date information, please visit our website at www.zyvex.com or email sales@zyvex.com.

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